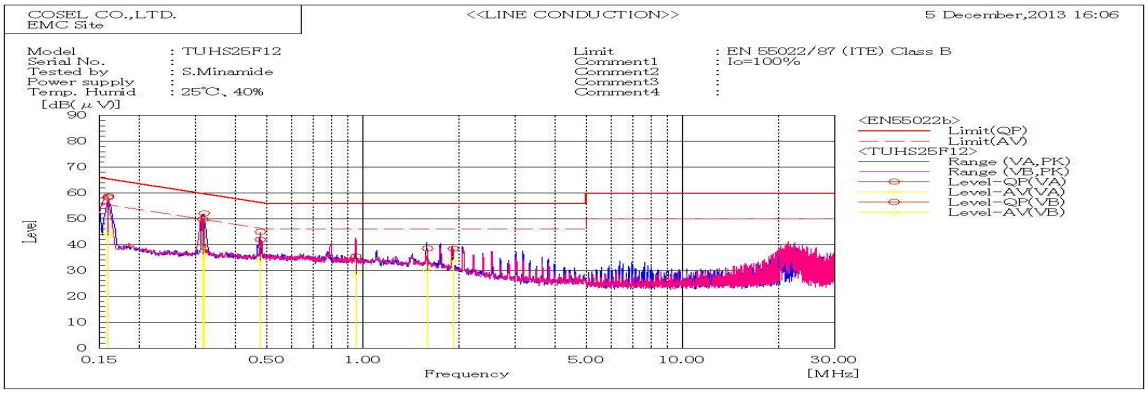
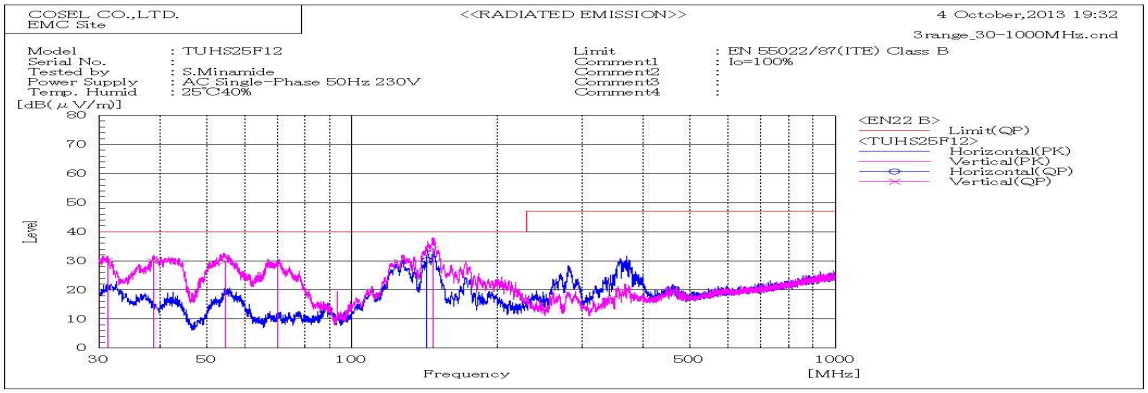
COSEL

DATA SHEET		Date	16-Dec-13
Model	TUHS25F12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.16018		VB	38.5	23.3	20.2	58.7	43.5	65.5	55.5	6.8	12	Pass	
0.15965		VA	38.1	24.1	20.2	58.3	44.3	65.5	55.5	7.2	11.2	Pass	
0.316		VB	29.8	16.1	20.1	49.9	36.2	59.8	49.8	9.9	13.6	Pass	
0.3194		VA	32	19.4	20.1	52.1	39.5	59.7	49.7	7.6	10.2	Pass	
0.47884		VA	21.9	13.9	20.1	42	34	56.4	46.4	14.4	12.4	Pass	
0.47903		VB	24.9	13.8	20.1	45	33.9	56.4	46.4	11.4	12.5	Pass	
0.95311		VB	15.3	8.4	20.2	35.5	28.6	56	46	20.5	17.4	Pass	
1.59634		VA	18.3	9.8	20.3	38.6	30.1	56	46	17.4	15.9	Pass	
1.92093		VB	18.2	14.2	20.3	38.5	34.5	56	46	17.5	11.5	Pass	

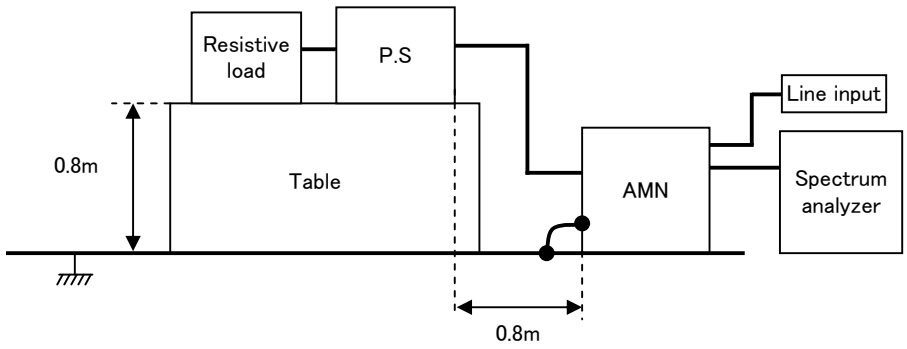


Frequency MHz	Polarization	Stability	Reading dB(uV)	Factor dB(1/m)	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
31.207	V	Stable	43.9	-13.8	30.1	40	9.9	Pass	107	1	
38.867	V	Stable	45.1	-15.3	29.8	40	10.2	Pass	101	68	
54.771	V	Stable	53.6	-23.8	29.8	40	10.2	Pass	109	93	
70.331	V	Stable	49	-20.6	28.4	40	11.6	Pass	135	120	
143.045	H	Stable	50.3	-20.1	30.2	40	9.8	Pass	157	282	
147.653	V	Stable	51.8	-17.8	34	40	6	Pass	102	188	

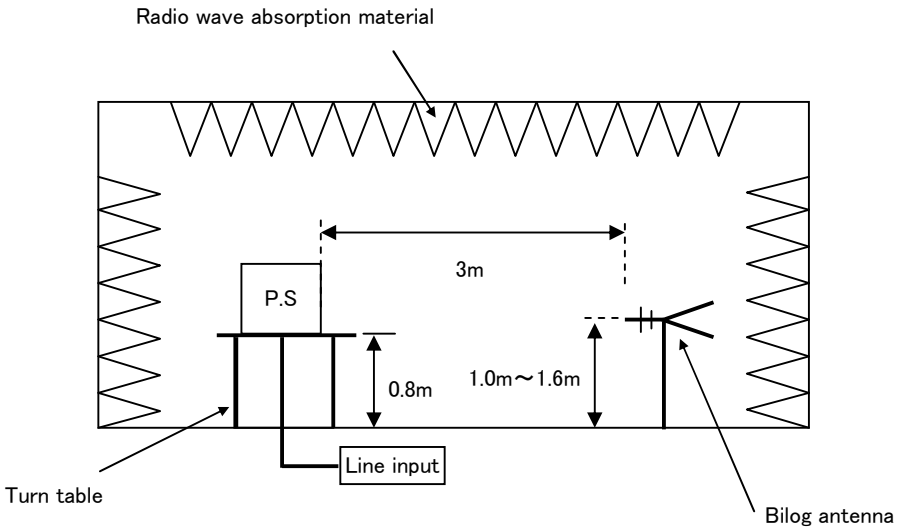
COSEL

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

1. Line conduction



2. Radiated emission



Conditions

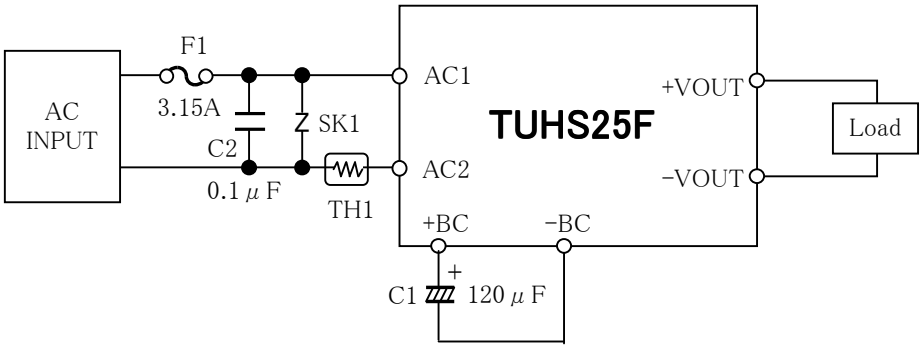
Test: EMI
Model Name: TUHS25F□□

○ Photographs of Test Set-Up

LINE CONDUCTION

RADIATED EMISSION

○ Test circuit



F1:	SLT250V3.15A (Nippon Seisen)	3.15A
TH1:	10D2-08LCS (SEMITEC)	10Ω
SK1:	S10K385E2K1 (TDK EPCOS)	

Fig.1 Testing circuitry